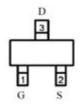
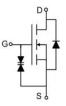


## **Main Product Characteristics:**

V <sub>DSS</sub>	60V			
R <sub>DS</sub> (on)	2.3Ω (Max)			
I <sub>D</sub>	0.3A			







SOT-23

**Pin Assignments** 

Schematic Diagram

## **Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature



# **Description:**

It utilizes the latest trench processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

## **Absolute Max Rating:**

Symbol	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V①	0.3		
I <sub>DM</sub>	Pulsed Drain Current ②	1.2	A	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation ③	0.35	W	
V <sub>DS</sub>	Drain-Source Voltage	60	V	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 150	°C	

## **Thermal Resistance**

Symbol	Characterizes	Тур.	Max.	Units
R <sub>θJA</sub>	Thermal Resistance,Junction-to-Ambient ④	_	357	°C/W





# **Electrical Characteristics** @T<sub>A</sub>=25℃ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	60	_	_	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA	
D	Static Drain-to-Source	_	2.1	2.87	Ω	V <sub>GS</sub> =4.5V,I <sub>D</sub> = 0.2A	
R <sub>DS(on)</sub>	on-resistance	_	1.8	2.3	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =0.3A	
V <sub>GS(th)</sub>	Gate threshold voltage	1	_	2.5	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
I <sub>DSS</sub>	Drain-to-Source leakage current	_	_	1	μA	V <sub>DS</sub> =60V,V <sub>GS</sub> =0V	
I <sub>GSS</sub>	Gate-to-Source forward leakage	_	_	±10	μA	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	
Qg	Total gate charge	_	1.9	_	nC	V <sub>DS</sub> =10V,I <sub>D</sub> =0.3A, V <sub>GS</sub> =4.5V	
Q <sub>gs</sub>	Gate-to-Source charge	_	0.3	_			
$Q_{gd}$	Gate-to-Drain("Miller") charge	_	0.7	_			
t <sub>d(on)</sub>	Turn-on delay time	_	2	_			
tr	Rise time	_	16	_	no	$V_{DD}$ =10V, $V_{GS}$ =10V, $I_{D}$ =0.2A $R_{GEN}$ =10 $\Omega$	
t <sub>d(off)</sub>	Turn-Off delay time	_	8	_	ns		
t <sub>f</sub>	Fall time	_	21	_			
Ciss	Input capacitance	_	30	_	pF	\/ 05\/\/ 0\/	
Coss	Output capacitance	_	12	_		V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, f=1.0MHz	
C <sub>rss</sub>	Reverse transfer capacitance	_	5	_		I – I.UIVII IZ	

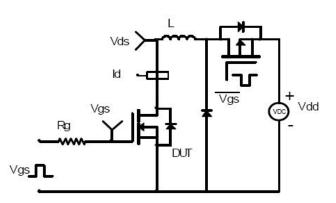
# **Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current	_	_	0.3	А	MOSFET symbol
	(Body Diode) ①					showing the
Ism	Pulsed Source Current	_	_	1.2	Α	integral reverse
	(Body Diode) ①					p-n junction diode.
V <sub>SD</sub>	Diode Forward Voltage	_	_	1.2	V	I <sub>S</sub> =0.3A, V <sub>GS</sub> =0V,T <sub>J</sub> = 25°C

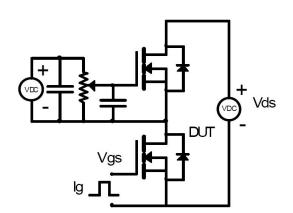


## **Test Circuits and Waveforms:**

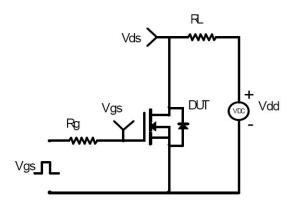
#### **EAS Test Circuit:**



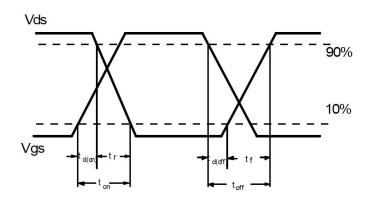
#### **Gate Charge Test Circuit:**



#### **Switching Time Test Circuit:**



#### **Switching Waveforms:**



**Version : Preliminary** 

### Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ④ The value of R<sub>θJA</sub> is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A$  =25  $\,^{\circ}$ C



# **Mechanical Data:**

# 

Symbol	Dimension I	n Millimeters	Dimension In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.95	STYP	0.037TYP		
e1	1.800	2.000	0.071	0.079	
Ĺ	0.55	REF	0.022REF		
L1	0.300	0.500	0.012	0.020	
θ	O <sup>0</sup>	8 <sup>0</sup>	00	8 <sup>0</sup>	





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